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# Time walk correction of CdTe detectors using depth sensing technique

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## Abstract.

A digital timing method aiming to minimize the time walk caused by the depth-dependent pulse shape variations in CdTe detectors has been developed. Detector pulses are digitized at the preamplifier stage and a full digital process is carried out to deduce and correct the time walk according to the interaction depth. A time resolution of **6.52 ns** FWHM at an energy threshold of **150 keV** with a CdTe detector ( $10\times 10\times 1\text{ mm}^3$ ) is achieved, which is close to the intrinsic resolution of the detector. The method improves the time resolution with no loss of detection efficiency and it is easy to implement. It is confirmed that the slow mobility and the short lifetime of the holes are major obstacles for further improvement in the timing performance of the CdTe detectors. The method is applicable to any semiconductor detector.

Keywords: Time walk, Semiconductor detectors, Depth sensing

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## 1      **1. Introduction**

2      CdTe detectors have many applications in the fields of nuclear physics, medical  
3      imaging and industry. Advantages of these detectors include good energy resolution,  
4      good detection efficiency, room temperature operation and high detector spatial  
5      resolution using **pixelated** detector arrays comprised of very small elements. However,  
6      the timing performance of these detectors is not satisfactory, when compared to other  
7      detectors such as modern scintillation detectors. A good timing resolution is desired for  
8      various applications such as timing measurements in nuclear physics experiments and  
9      particularly for medical imaging using positron emission tomography (PET), where the  
10     CdTe detectors have shown to be a very promising candidate [1-3]. The timing  
11     performance of CdTe detectors is mainly limited by the variations in the shape of detector  
12     pulses and also electronic noise. Variation in the shape of detector pulses **is due to the**  
13     **fact that** the drift velocity of holes is approximately a tenth of that of electrons [4], and  
14     hence the shape of signals from a CdTe detector strongly depends on the interaction  
15     depth, **i.e. where the electrons and holes are created in the detector**. Variation in the shape  
16     of pulses leads to a significant timing error when the conventional timing methods such  
17     as leading edge or constant fraction discrimination (CFD) are used. This timing error is  
18     commonly referred to as “time walk”.

19     The Amplitude and Rise-time Compensation (ARC) mode of operation is the most  
20     common method for minimizing the time walk caused by charge collection time  
21     variations [5, 6]. ARC timing generates a timing marker that is independent of amplitude  
22     and rise-time, provided each pulse has a constant slope throughout its leading edge.  
23     However, real pulses from planar CdTe detectors exhibit constant slope only for the  
24     pulses with either minimum or maximum rise-time and many pulses are a mixture of  
25     these two shapes depending on the interaction depth. As a result of this deviation from  
26     the ideal linear rise, ARC timing does not provide perfect compensation for the rise-time  
27     variations of CdTe detectors.

28     In order to more completely remove the slope-dependent time walk, timing methods  
29     have been developed which operate based on an event-by-event correction of the time  
30     walk, according to the detector pulse shape. However, the practical use of these methods  
31     is limited by the complicated electronic system required or limitation for application to

1 on-line measurements [7-11]. In a recent paper, it was shown that methods based on  
2 digital processing of the detector signals can be used for improving the timing  
3 performance of CdTe detectors [12]. In the present paper, a more detailed procedure for  
4 digital correction of time walk caused by the variations in the shape of detector pulses is  
5 presented. The method is based on the fact that the time walk is correlated with the rise-  
6 time of pulses and, therefore, one can use a rise-time measurement to deduce the time  
7 walk, in order to improve the timing performance. This is analogous to the improvement  
8 of energy resolution of CdTe detectors with the depth of interaction correction [13, 14],  
9 because pulse rise-time reflects the depth of interaction, as well. The paper is organized  
10 as follows: In Section 2 the details of the method are described. Section 3 describes the  
11 experimental setup. Section 4 discusses the results and Section 5 summarizes the paper.

## 12 13 **2. Description of the method**

14 Due to the considerable difference in the mobility of electrons and holes, the output  
15 waveform of a preamplifier, connected to a CdTe detector, strongly depends on the  
16 interaction depth, where the charge is released in the detector crystal. The relation  
17 between the pulse rise-time and interaction depth is illustrated in Fig. 1. In addition to the  
18 pulse shape variations due to the different depths of interaction, further variation in the  
19 shape of detector pulses may be caused by the charge trapping and de-trapping in the  
20 detector crystal and also non-uniformities of the electric field [15]. As a result of the great  
21 variations in the shape of detector pulses, a significant time walk results, when the  
22 conventional CFD method is used. In the CFD triggering, the input pulse is inverted,  
23 delayed and then added to the attenuated original pulse to form a bipolar pulse with a  
24 zero crossing point. The discriminator detects this point and generates the corresponding  
25 timing output pulse. Since the time of zero crossing is a function of pulse rise-time, the  
26 time walk increases with the depth of interaction, which is defined as the distance of the  
27 interaction point from the detector cathode. The ARC timing tries to minimize this effect  
28 by applying the CFD technique to the early part of the pulse [5, 6]. In this method, the  
29 detector pulses are shaped with a small shaping time constant, in order to reduce the noise  
30 and pulse duration, and the arrival time of the pulses is derived by setting a delay on the  
31 CFD, which is substantially shorter than the minimum rise-time of the pulses. The choice

1 of short delay makes the zero-crossing occur in the early part of the pulse, leading to a  
2 degree of immunity to the slope changes of pulses. However, the choice of delay is  
3 practically limited because if the delay is very small, for some events the CFD process  
4 can not transform the pulse to a bipolar pulse and the pickoff time would be generated  
5 by the random noise on the pulse baseline. This type of timing error occurs for pulses  
6 with long rise-times and for pulses that exceed the threshold level by only a small  
7 amount. Consequently, the ARC timing can not completely compensate for the time walk  
8 of the pulses that experience a slope change early in their rise. This slope-change-  
9 dependent time walk is a function of pulse shape, which is determined by the depth of  
10 interaction. Our correction procedure is to find this function and correct the time pickoff,  
11 generated by the ARC timing method. To do so, we group the pulses of similar rise-time  
12 together and the contribution of each group of pulses in the ARC timing of the CdTe  
13 detector is determined. This is done by employing a digital rise-time discriminator to  
14 group the pulses and a digital zero-crossing CFD for implementation of ARC timing. The  
15 details of the rise-time discrimination and procedure of time pickoff are described in the  
16 [Sections 2.1 and 2.2](#). When the time spectra of the different groups of pulses are  
17 compared, the time walk is manifested in the systematic time delays between the time  
18 spectra, from which one can generate a set of correction factors for compensating the  
19 time walks in the time pickoffs of different groups of pulses. The correction factor for  
20 each group of pulses is determined by calculating the time difference between the peak  
21 position of the relevant time spectrum and the peak position of the spectrum associated  
22 with the fast pulses originating from the vicinity of the cathode, for which the time walk  
23 is negligible. The time walk is then corrected by subtracting the correction factor from  
24 the time pickoffs, derived by the standard ARC timing.

25 In addition to the charge collection time variations, the timing performance of a CdTe  
26 detector is affected by the electronic noise. However, in practice the CFD parameters are  
27 chosen to overcome the charge collection time variations, rather than less significant  
28 electronic noise. Since in our method the pulses are divided into several groups, the  
29 variation in the rise-time of pulses within each group of pulses is reduced and, therefore,  
30 the timing parameters can be set to yield a better suppression of noise. Applying a  
31 variable pulse shaping and CFD delay process to the different groups of pulses leads to

1 systematic time offsets between the time pickoffs. Nevertheless, the time offsets are fixed  
2 and, therefore, all the pulses can be synchronized by compensating the time offsets. This  
3 is done by applying a second correction factor to the one derived for the time walk  
4 correction. In practice, both the correction factors are combined together to form a total  
5 correction factor, which is simply determined by comparing the peak position of the time  
6 spectra. The complete procedure of timing is illustrated in Fig. 2. The procedure can be  
7 summarized in three steps: (1) the rise-time of each pulse is evaluated, (2) a time pickoff  
8 procedure, tailored in accordance with the pulse rise-time, is implemented and (3) a  
9 correction factor is applied to correct the time walk and synchronize the time pickoffs. It  
10 should be mentioned that the correction factors need to be determined by offline analysis  
11 of the pulses. Nevertheless, the method can be used for online measurements once the  
12 correction factors are known. **In addition to time walk correction, the rise-time  
13 information can be used to improve the energy resolution by compensating the pulse  
14 deficit due to charge trapping inside the detector [16].**

### 16 *2.1. Rise-time discriminator*

17 To evaluate the rise-time of pulses, a straightforward approach is to directly measure it  
18 at the preamplifier output. However, the high frequency noise at the preamplifier output  
19 limits the accuracy of such a measurement. We evaluated the rise-time of pulses by  
20 measuring their peaking time after shaping with a digital CR-RC shaping filter [16]. A  
21 CR-RC filter drastically reduces the noise, while still information on the rise-time of  
22 pulses is reflected in the peaking time of the filtered pulse. This approach is  
23 computationally very fast and at the same time prepares the pulses for extraction of  
24 energy information as well. The peaking time of the pulses is determined by calculating  
25 the time required for a pulse to change from 10% to 100% of the pulse amplitude. The  
26 shaping time constant of the filter is decided in accordance with the best energy  
27 resolution of the detector.

### 28 *2.2. Time pickoff procedure*

29 In the ARC timing of semiconductor detectors, before sending a pulse to a CFD,  
30 additional shaping is required to minimize the noise and reduce the duration of pulses. In  
31

1 the analogue regime this task is performed by using a timing filter amplifier that performs  
2 independent differentiation and integration on the preamplifier pulses. In our study, pulse  
3 shaping is performed using a digital CR-RC filter. The digital domain provides a flexible  
4 approach in performing the integration and differentiation functions in order to set the  
5 optimum shaping time constants. The optimal shaping time constant of the filter is  
6 decided by comparing the time resolutions obtained using different shaping time  
7 constants. After pulse shaping, the pulses are sent to a digital version of zero-crossing  
8 CFD [12, 17] with an optimized delay on the CFD, corresponding to the ARC mode of  
9 operation. The CFD delay is optimized by performing multiple analyses on the pulses.

### 11 3. Experimental setup

12 The procedure of time walk correction is examined by using an experimental setup  
13 including a Schottky CdTe detector, a fast liquid scintillator detector and a fast digital  
14 oscilloscope as waveform digitizer. The schematic diagram of our experimental setup is  
15 shown in Fig. 3. A Schottky CdTe detector is placed against a small fast liquid scintillator  
16 (NE213 scintillator with a cylindrical volume of 2" long by 2" diameter), coupled to a  
17 **Photomultiplier Tube (PMT) of type R329**. The size of the Schottky CdTe detector is  
18  $10 \times 10 \times 1 \text{ mm}^3$  and it is fabricated by evaporating platinum and indium as electrodes onto  
19 the surface of a CdTe wafer [18]. The detector is encapsulated in an aluminum box with a  
20 BNC connector for connection to a fast charge-sensitive preamplifier (Amptek 250 [19]).  
21 The preamplifier has a rise-time of 5 ns. The detector is connected to the preamplifier  
22 through a de-coupling capacitor. Tests were performed using a  $^{22}\text{Na}$  point source. **The**  
23 **source and detector are placed in a way that radiation enters from the detector side. This**  
24 **geometry helps to capture more coincident events when the oscilloscope is triggered on**  
25 **the CdTe detector signals**. The CdTe detector is operated at a bias voltage of 300 V. In  
26 this operating condition, the maximum transit times for electrons and holes are  $\sim 350 \text{ ns}$   
27 and  $\sim 3.2 \mu\text{s}$ , respectively. **At this voltage, the detector is fully depleted and the motilities**  
28 **of electrons and holes are saturated so that no further improvement in the signal rise time**  
29 **is observed at higher voltages**. The measurements were performed at room temperature.  
30 To avoid the polarization phenomenon that affects Schottky CdTe detectors [20], the  
31 detector bias voltage was reset every 10 min.

1 The preamplifier and the PMT outputs are simultaneously digitized by means of the  
2 Lecroy WavePro7000 digital storage oscilloscope at a sampling rate of 5 GS/s and 8 bit  
3 resolution. The oscilloscope is set to trigger on the CdTe detector signals. Around 50,000  
4 pairs of pulses were stored on the hard disk drive of the oscilloscope of which a  
5 considerable number are due to the 511 keV coincidence  $\gamma$ -rays. The digitized pulses are  
6 transferred to a personal computer for offline analysis. The offline analysis is performed  
7 using a program written in MATLAB<sup>®</sup> language.

#### 8 9 **4. Results**

10 In order to calibrate the energy scale of the system, the energy information of pulses is  
11 extracted after a CR-RC shaping filter with 3  $\mu$ s shaping time constant. The energy  
12 spectrum of <sup>22</sup>Na is shown in Fig. 4. Performing the energy calibration of the system,  
13 using the 511 keV positron annihilation peak and the 1275 keV  $\gamma$ -ray of <sup>22</sup>Na, **the energy**  
14 **threshold of the system is set at 150 keV.** Then, a digital ARC timing procedure is  
15 initially performed on the pulses of the CdTe detector. The output pulses of the CdTe  
16 detector were shaped by a fast digital CR-RC filter with 15 ns shaping time constant. The  
17 arrival times of the pulses were then determined by feeding the shaped pulses to a digital  
18 zero-crossing CFD with 23 ns CFD delay and 0.24 attenuation factor, according to the  
19 best time resolution. With regard to the NE213 detector, since the pulses do not have the  
20 undesirable characteristics of variation in the pulse shape, no shaping is done on the  
21 pulses, and the arrival time is determined by direct application of a simple digital  
22 constant-fraction discriminator [15] to the PMT signals. The spectrum of the time  
23 difference between the arrival times of pulses from the two detectors is shown in Fig. 5.  
24 The spectrum represents a time resolution of **10.1 ns FWHM.** Due to the negligible  
25 contribution of the scintillator detector to the time spectrum ( $\sim$ 1 ns FWHM), the FWHM  
26 of the time spectrum is considered to be the time resolution of the CdTe detector. The  
27 spectrum has an asymmetric shape and suffers from a tail, which is attributed to the slow  
28 rise-time events. The tail is a major problem in timing measurements with CdTe  
29 detectors, as a tight time window can cause a drastic loss in detection efficiency.

30 In the next step, the depth sensing technique is employed to correct the time walk. The  
31 depth of interaction is evaluated using the time discriminator that measures the peaking



1 time of the pulses after shaping with the digital CR-RC filter, used for the energy  
2 measurement. The shaping time constant of the filter is  $3\ \mu\text{s}$ , corresponding to the best  
3 energy resolution. A distribution of peaking times is shown in Fig. 6. The distribution is  
4 not symmetric due to the off-center position of the source in front of the detector. The  
5 calculated peaking times are grouped into 6 bins as shown in the Figure and the timing  
6 spectrum of pulses associated with each bin is obtained against the scintillator detector.  
7 At this stage, the same pulse shaping and CFD procedures with those of Fig. 5 are applied  
8 to all groups of pulses. The results of these measurements, effectively as a function of  
9 depth of interaction, are shown in Fig. 7. The best timing resolution of less than  $4.26\ \text{ns}$   
10 FWHM is recorded at depth parameter 1, corresponding to the pulses from  $\gamma$ -rays  
11 interacting close to the cathode of the detector. It is seen that the time resolution  
12 decreases as the depth of interaction increases and the widest spectrum results from the  
13 group of pulses originating from the vicinity of the anode, with a time resolution of  $\sim 50$   
14 ns FWHM. The relative positions of the time spectra, associated with different depths of  
15 interactions, are shown in Fig. 8. Due to the walk in the time pickoffs, the peak positions  
16 show a marked dependency on the depth of interaction. In fact, a time difference of  $20\ \text{ns}$   
17 is observed between the time spectra of pulses originating from the two ends of the  
18 detector. The depth effect is corrected by deducing a correction factor from the CFD  
19 outputs of each group of pulses. The correction factor of each group is the difference  
20 between the peak position of the associated time spectrum and the time spectrum of the  
21 pulses associated with the depth parameter 1. The time spectrum resulting from the depth  
22 correction method is shown in Fig. 9. The time resolution improves to  $7.12\ \text{ns}$  and the tail  
23 of the spectrum caused by the slow events is considerably diminished. It is worth  
24 mentioning that the improvement is achieved without affecting the detection efficiency. If  
25 the detection efficiency is not so critical, the spectra with distorted timing resolution can  
26 be rejected to use only the best time resolution. This is a similar procedure to the slow  
27 Rise-time Reject (SR) timing mode, which is provided in the standard analogue CFD  
28 modules.

29 In addition to the time walk correction, a further improvement in the procedure of time  
30 pickoff is to minimize the noise effect. For this purpose, pulse shaping and CFD  
31 parameters are separately optimized for each group of pulses. The signal-to-noise ratio is

1 improved by making a slight increase in the shaping time constant of the digital timing  
2 filter, in accordance with the rise-time of the pulses. A considerable increase in the CFD  
3 delay is also made to make the zero crossing at the optimum point of slope-to-noise ratio.  
4 Again the time spectra of different groups of pulses are obtained and the correction  
5 factors for compensating the time walk and the time offset caused by the different  
6 procedures of time pickoff are determined by comparing the new time spectra. The  
7 overall time spectrum, after applying the final correction factors, is shown in Fig. 10. A  
8 time resolution of 6.52 ns FWHM is achieved. Table 1 presents a comparison of time  
9 resolution measurements using 1 mm thick CdTe detectors. The best time resolution is  
10 reported by Ueno [3] as 4.25 ns. However, the energy threshold of this measurement is  
11 450 keV which only covers the photo-peak area, leading to a drastic loss of detection  
12 efficiency. The result of the present work is slightly better than the result of ref. [12] in  
13 which time walk is compensated through a rough categorization of signals into two  
14 groups. This implies that our result is very close to the intrinsic resolution of the detector  
15 as no further improvement of time resolution can be achieved without sacrificing the  
16 detection efficiency by discarding the slow signals or increasing the energy threshold.

17 Although the measurement results show that the technique can improve timing  
18 resolution in comparison with the conventional ARC timing, the time resolution of slow  
19 events is still very broad (~50 ns FWHM). In fact, the degree to which the timing  
20 performance can be improved is limited by the poor performance of the slow rise-time  
21 events. The poor timing performance of these events is explained by the fact that, in  
22 addition to the time walk caused by the variations in the charge collection time, the  
23 timing performance is strongly affected by the slope-to-noise effect as well. If  $e_n$  is the  
24 voltage amplitude of the noise superimposed on the analog pulse, and  $dV/dt$  is the slope  
25 of the signal when its leading edge crosses the discriminator threshold, the timing  
26 uncertainty due to the electronic noise is given by the slope-to-noise ratio:

27 Timing error =  $e_n / (dV/dt)$ . (1)

28 If the noise cannot be reduced, the minimum timing error is determined by the  
29 maximum slope on the analog pulse. Due to the low mobility of holes, for the pulses that  
30 have their time pickoff determined by the hole's contribution to the pulse, the achievable

1 slope-to-noise ratio is limited and therefore greater timing errors are expected. In fact, the  
2 pulse slope for hole-dominant pulses is around ten times slower than the electron-  
3 dominant pulses, which is in agreement with the timing results. The timing resolution of  
4 pulses from depth parameter 6 is around ten times larger than that of the pulses from the  
5 depth parameter 1. Further deterioration of timing performance stems from hole trapping.  
6 Because the hole's lifetime is so much shorter than the hole transit time, the pulse  
7 amplitude is very dependent upon the depth of interaction and the collected charge is  
8 significantly reduced with increasing path length. This affects the time resolution by  
9 changing the shape of pulses and reducing the slope-to-noise ratio. Fig. 11 shows the  
10 energy spectra as a function of interaction depth. The peak positions show a marked  
11 depth dependence which is due to the charge trapping effect. Since both rise-time and  
12 pulse amplitude are correlated with the depth of interaction, in a similar manner with the  
13 time walk correction, one can use the depth data to deduce the charge collection  
14 efficiency and thus improve the spectroscopic performance.

## 15 16 **5. Summary**

17 A new timing method has been presented that can correct timing information that is  
18 distorted by time walk. In addition, the method leads to a better suppression of noise  
19 contribution and full detection efficiency is guaranteed. **The method is performed by**  
20 **using a simple algorithm for** rise-time evaluation and it is extendable to all semiconductor  
21 detectors. It is confirmed that the low mobility of holes and hole trapping are major  
22 obstacles to timing performance. The method can be used for online measurements once  
23 the calibration is done.

## 24 25 **Acknowledgment**

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27 University in Japan for providing the detectors and digitizer. We acknowledge the  
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21

## 22 **Tables**

23 Table 1. Results of time resolution measurements using 1 mm thick CdTe detectors

24

## 25 **Figures Captions**

26

27 Figure 1. Relationship of interaction depth to detector pulse shape. Three interaction  
28 positions are shown leading to three different waveforms. Position 1 illustrates the case  
29 where charge is produced very close to the cathode and the pulse is due to the motion of  
30 the electrons. Position 2 is a case that charge is produced at a mid-point between the  
31 anode and cathode so that the pulse is due to both electrons and holes. An abrupt slope

1 change is observed as the electrons reach to their electrode. In case 3, the charge is  
2 produced very close to anode and the pulse is due entirely to the motion of the holes.

3  
4 Figure 2. Details of the time pickoff procedure. **In addition to time walk correction, the**  
5 **depth data can be used for improving the energy resolution through compensating for**  
6 **charge trapping.**

7  
8 Figure 3. Schematic diagram of the setup used for the timing measurements.

9  
10 Figure 4. The energy spectrum of  $^{22}\text{Na}$  measured with the CdTe detector. The energy  
11 threshold is approximately 150 keV.

12  
13 Figure 5. Timing spectrum between the Schottky CdTe detector and the liquid  
14 scintillator. The width of the spectrum is **10.1 ns FWHM**. The energy threshold is **~ 150**  
15 **keV**.

16  
17 **Figure 6. Distribution of signal peaking time. The asymmetric shape of the spectrum**  
18 **stems from the off-center position of the source in front of the detector.**

19  
20 Figure 7. Timing spectrum vs depth of interaction. The time resolutions (FWHM) of the  
21 spectra from anode to cathode are, respectively, 4.26, 5.55, 8.45, 13.63, 25 and 50 ns.

22  
23 Figure 8. The relative position of time spectra associated with different parts of the  
24 detector.

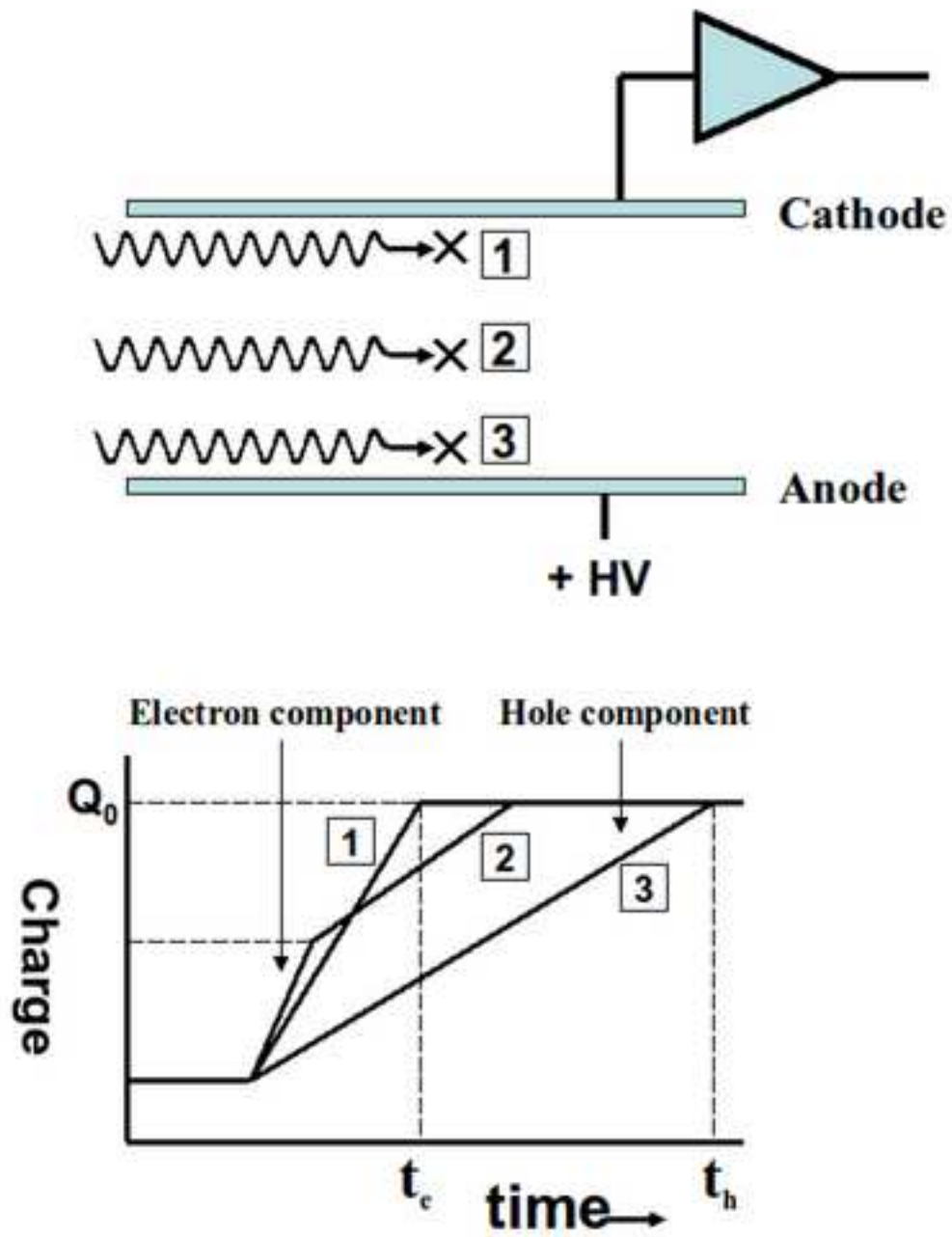
25  
26 Figure 9. Comparison of timing spectra before and after time walk correction. (A)  
27 standard ARC timing, (B) after time walk correction.

28  
29 Figure 10. Improvement of time spectra by applying different procedures of time pickoff.  
30 (A) standard ARC timing, (B) after time walk correction and noise minimization.

31

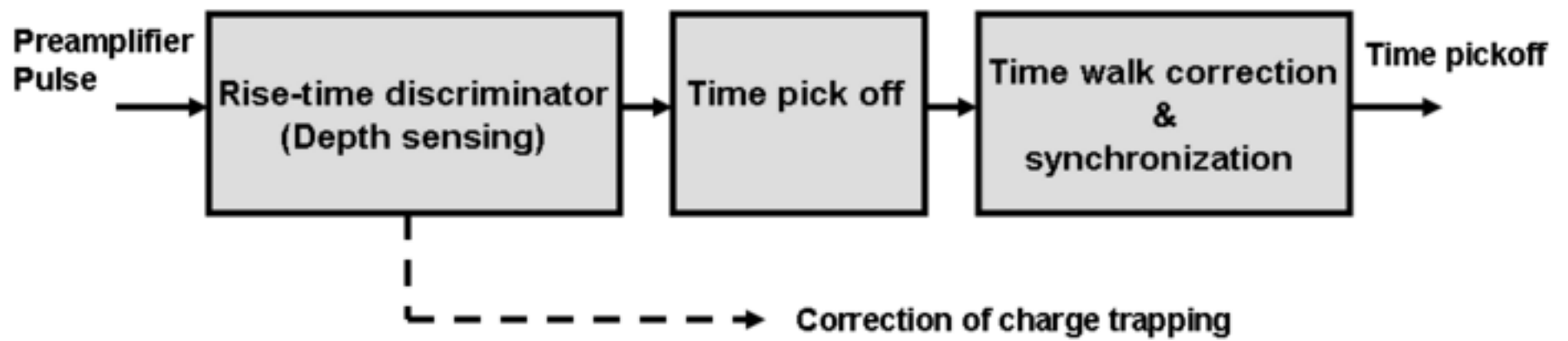
1 Figure 11. Energy spectra of  $^{22}\text{Na}$  as a function of depth parameter.  
2

Figure(1)  
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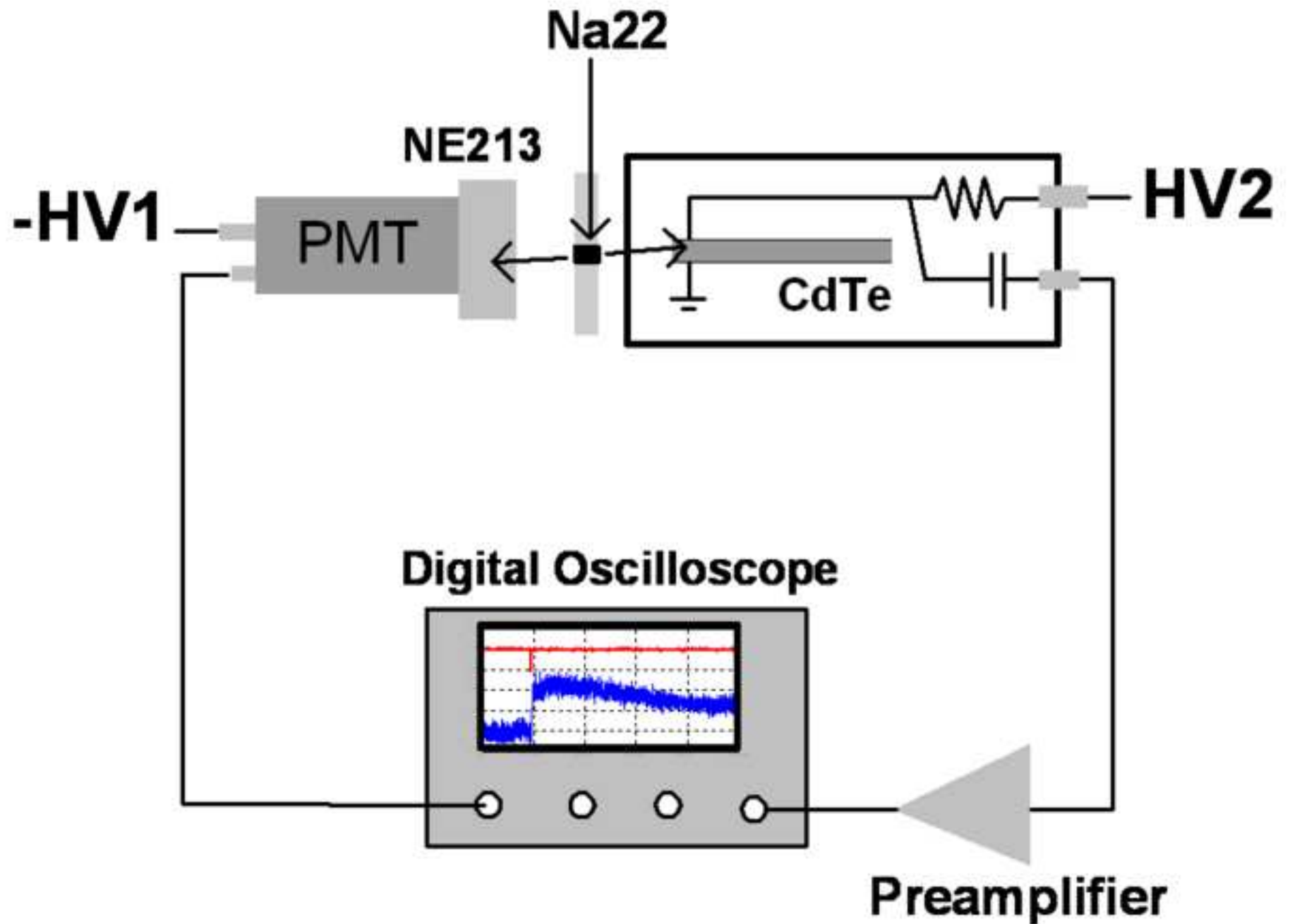
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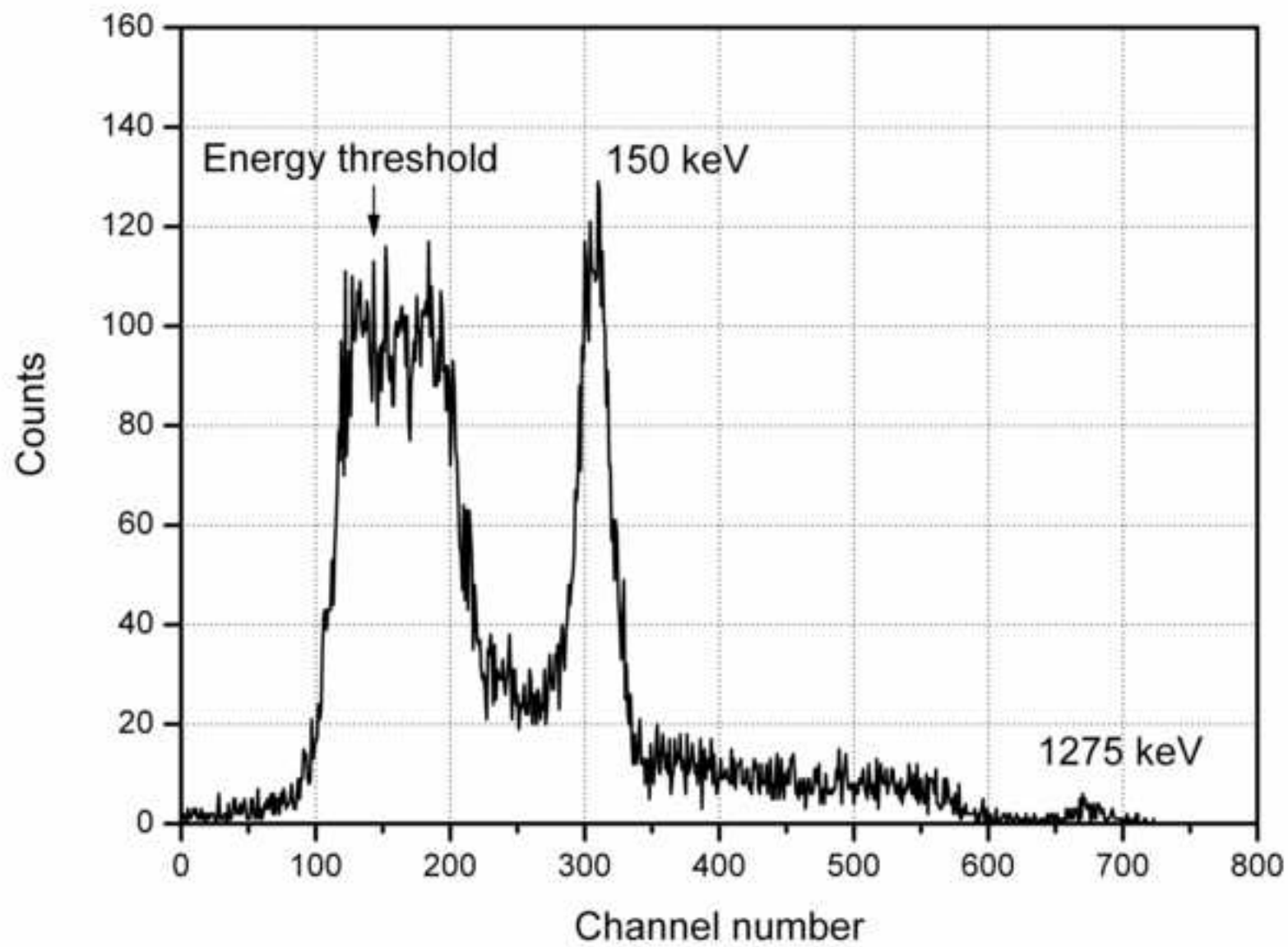


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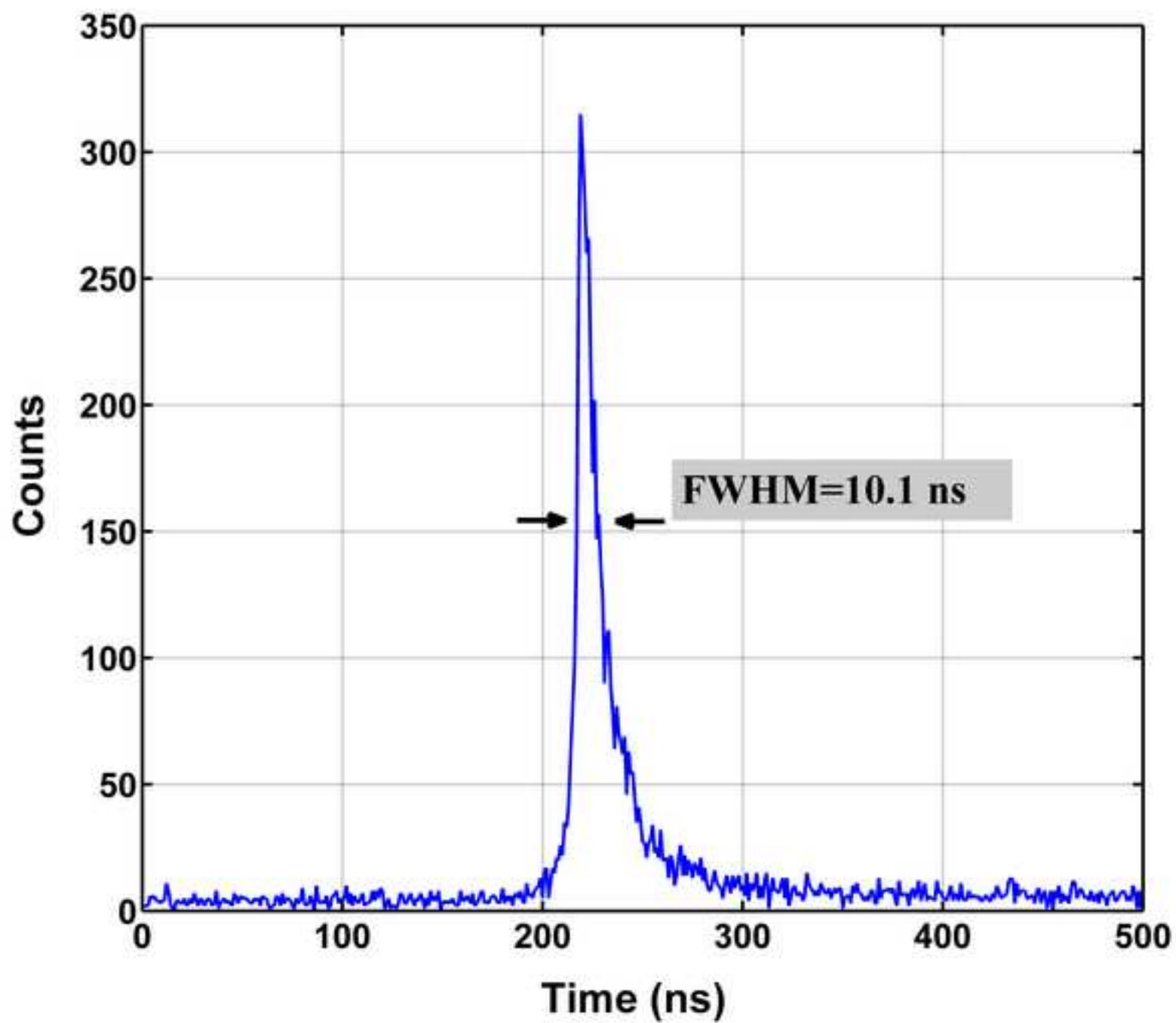
Figure(4)

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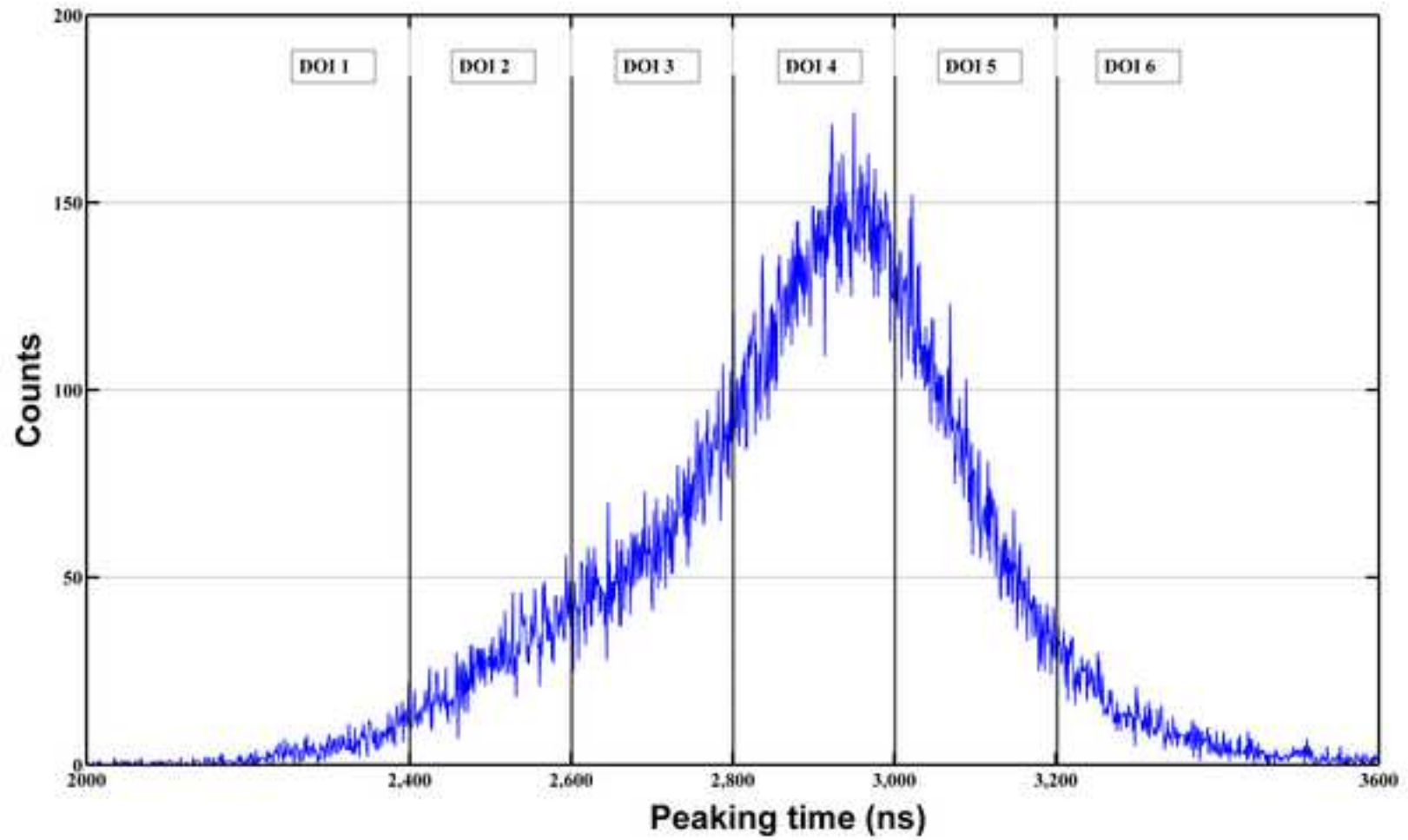


Figure(5)

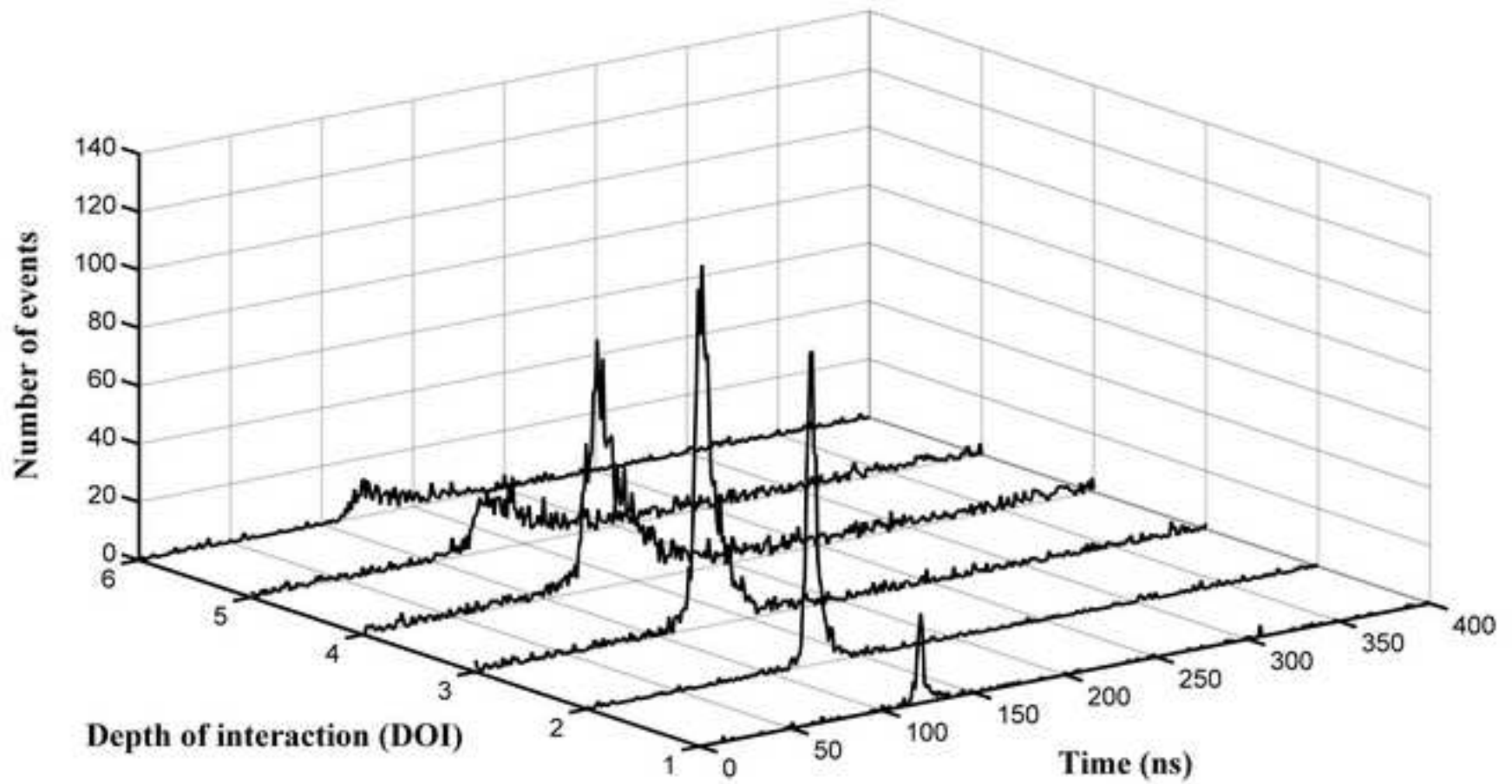
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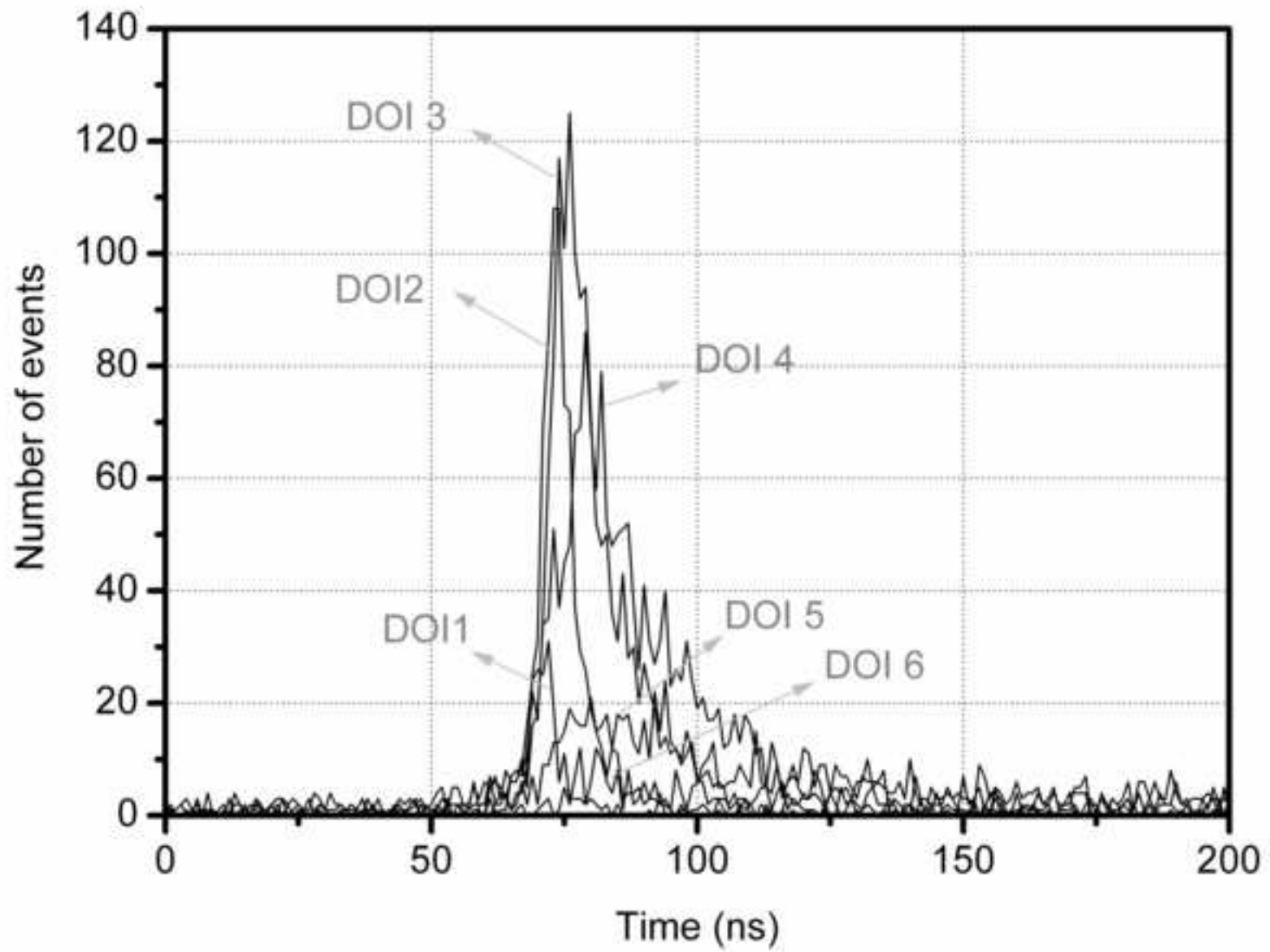
Figure(6)  
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Figure(7)  
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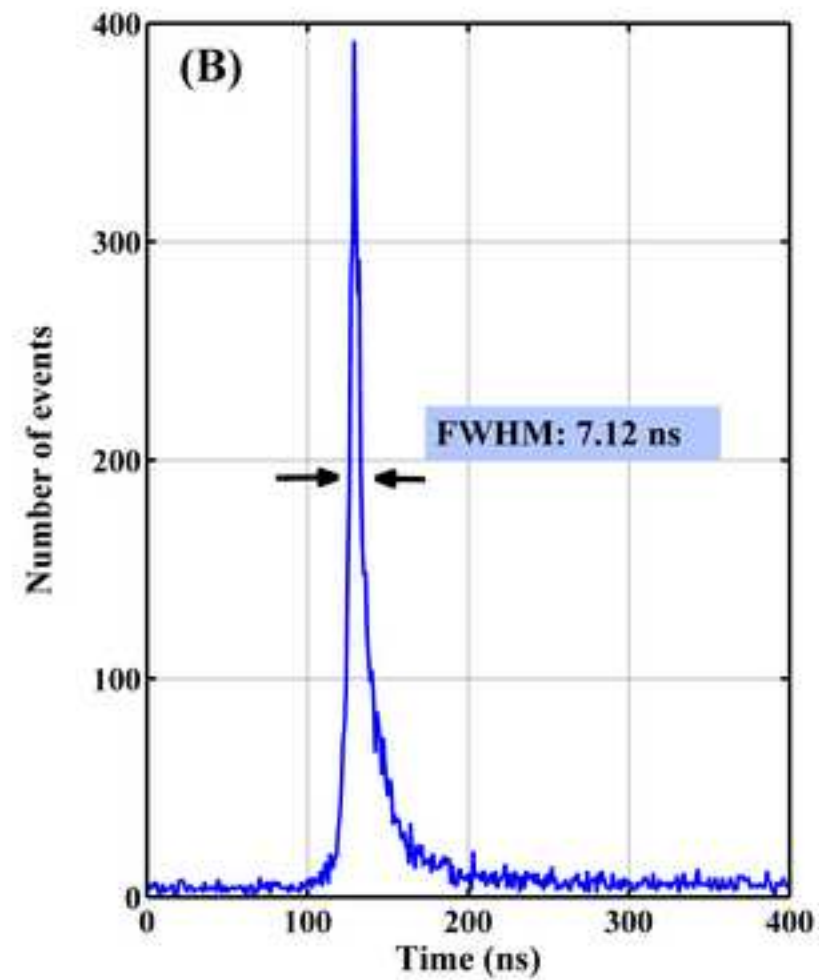
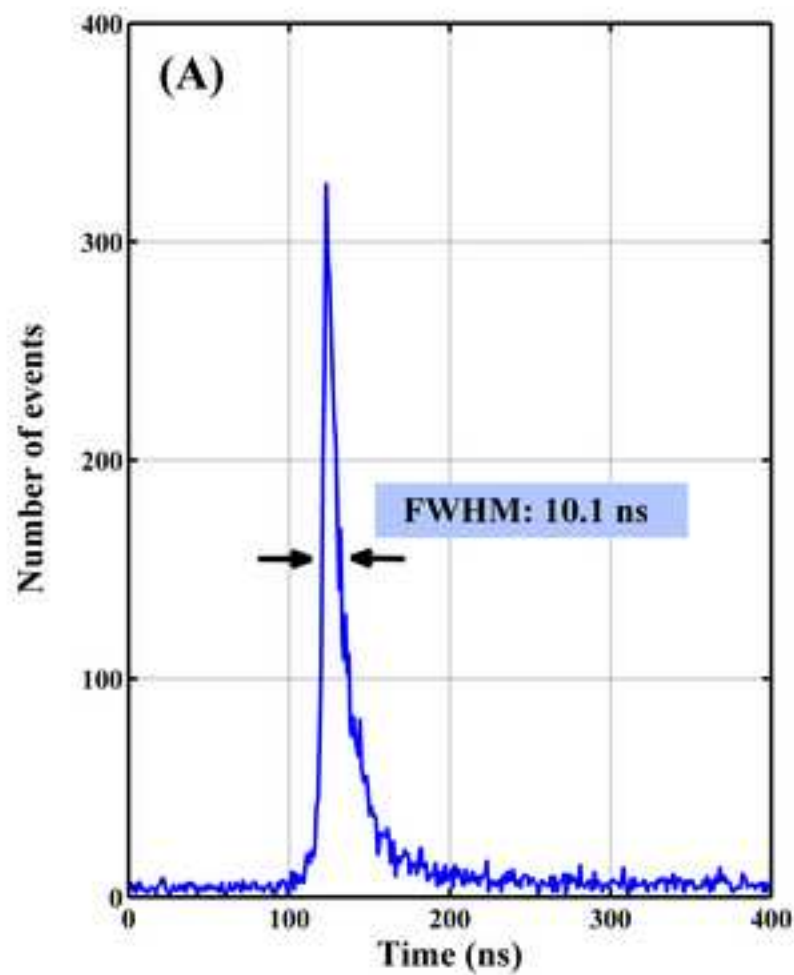


Figure(8)  
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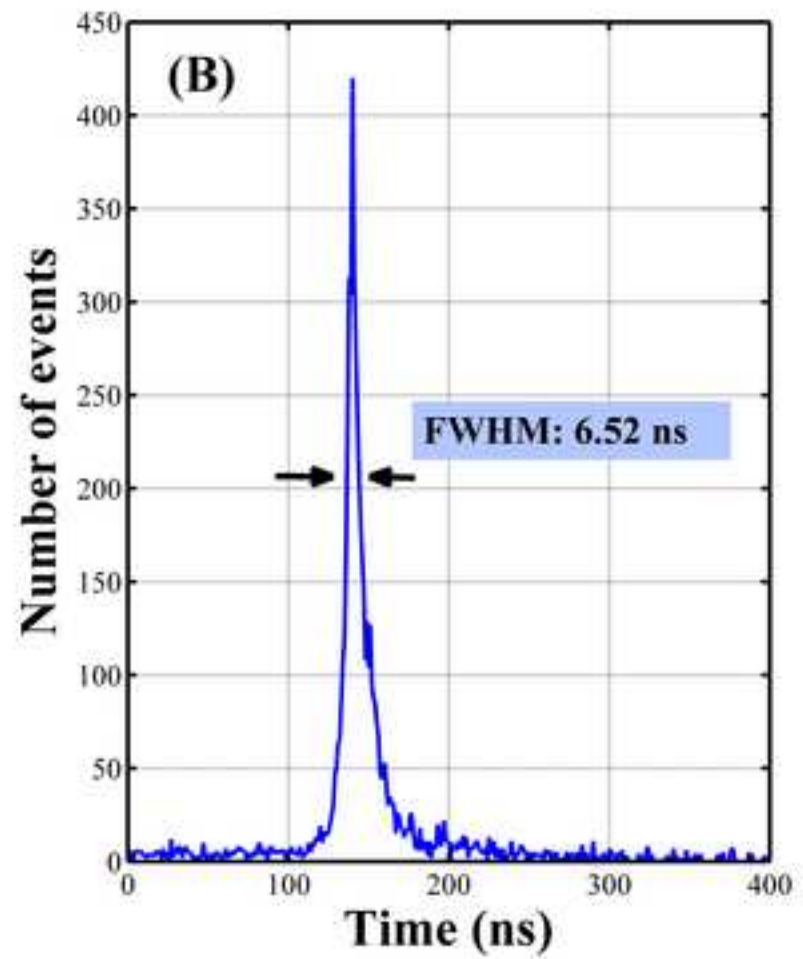
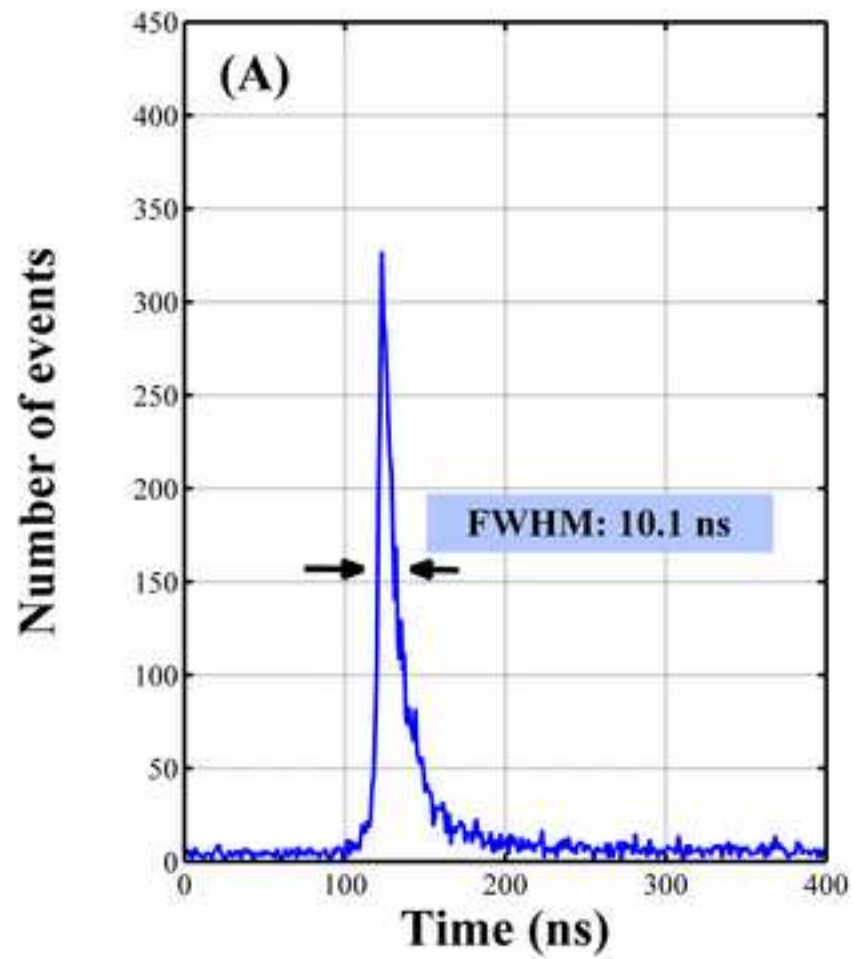
Figure(9)

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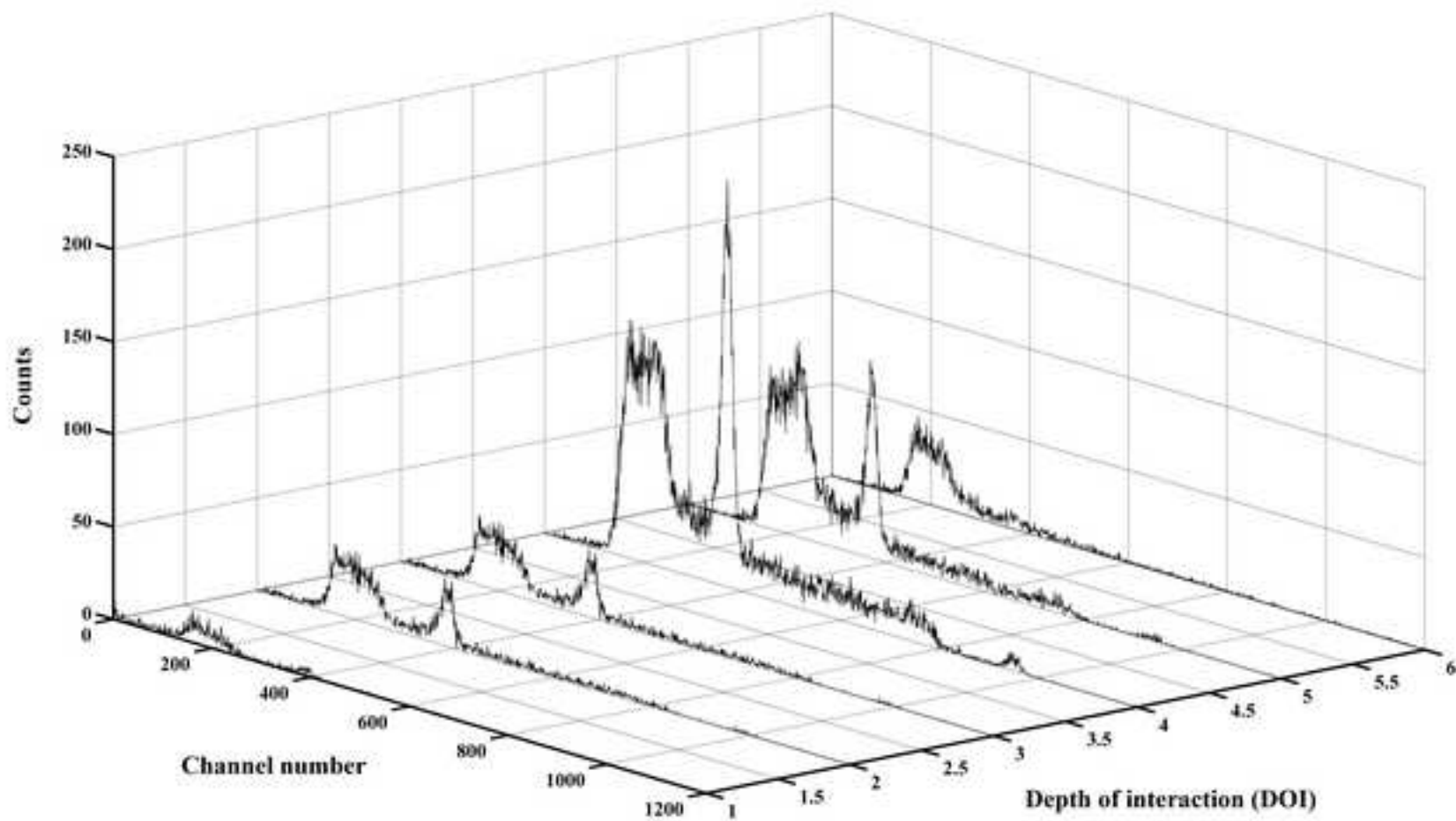
Figure(10)

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Figure(11)  
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Table(1)

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<b>Resolution</b>	<b>Energy threshold</b>	<b>Method</b>	<b>Temperature</b>	<b>Reference</b>
6.52 ns	150 keV	Digital	Room Temp.	Present work
4.255 ns	450 keV	Analog	Room Temp.	[3]
7.2 ns	150 keV	Digital	Room Temp.	[12]
9.6 ns	150 keV	Analog	-20 C	[21]

List of changes, reviewer #2

1. In order to be able to compare the results of this work with the results of the previous paper, the energy threshold of the measurements was set at 150 keV, the same as that of a previous paper ( NIMA vol 606, p. 681, 2009). Results obtained under the new conditions were compared with the literature data for 1 mm thick CdTe detector. Corrections in page 3, lines 1-3 and page 9, lines 7-15.
2. Page 2, line 10, new reference was included. In discussion the result of the reference was added, page 9, line 7-15 and Table 1.
3. Page 2, line 13, a reference was added.
4. Page 6, line 17, type of PMT was indicated.

List of changes, reviewer #1

Page 1, line 5, pixilated was corrected.

Page 4, line 16, Sections 3.1 and 3.2 was corrected to sections 2.1 and 2.2.

Page 5, line 16, corrected.

Page 5, line 29, corrected.

Page 6, lines 27-29, it was explained that at this voltage motilities are saturated therefore, an improvement of signal rise time can not be expected.

Page 8, line 13, cathode was replaced by anode.

Page 8, line 3-5, a distribution of signal peaking time was included.

Page 8, line 4-5, and page 66, lines 22-25, and figure 3, corrections was made to clarify that the interactions do not occur uniformly across all depth due the geometry of the experiment.

Page 9 lines 14-15, explanation was included to clarify the intrinsic resolution.